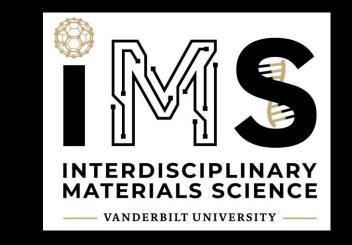
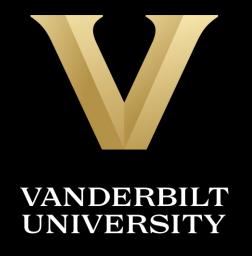
Parameter Space for Fabricating Atomically Thin Proton Exchange Membranes

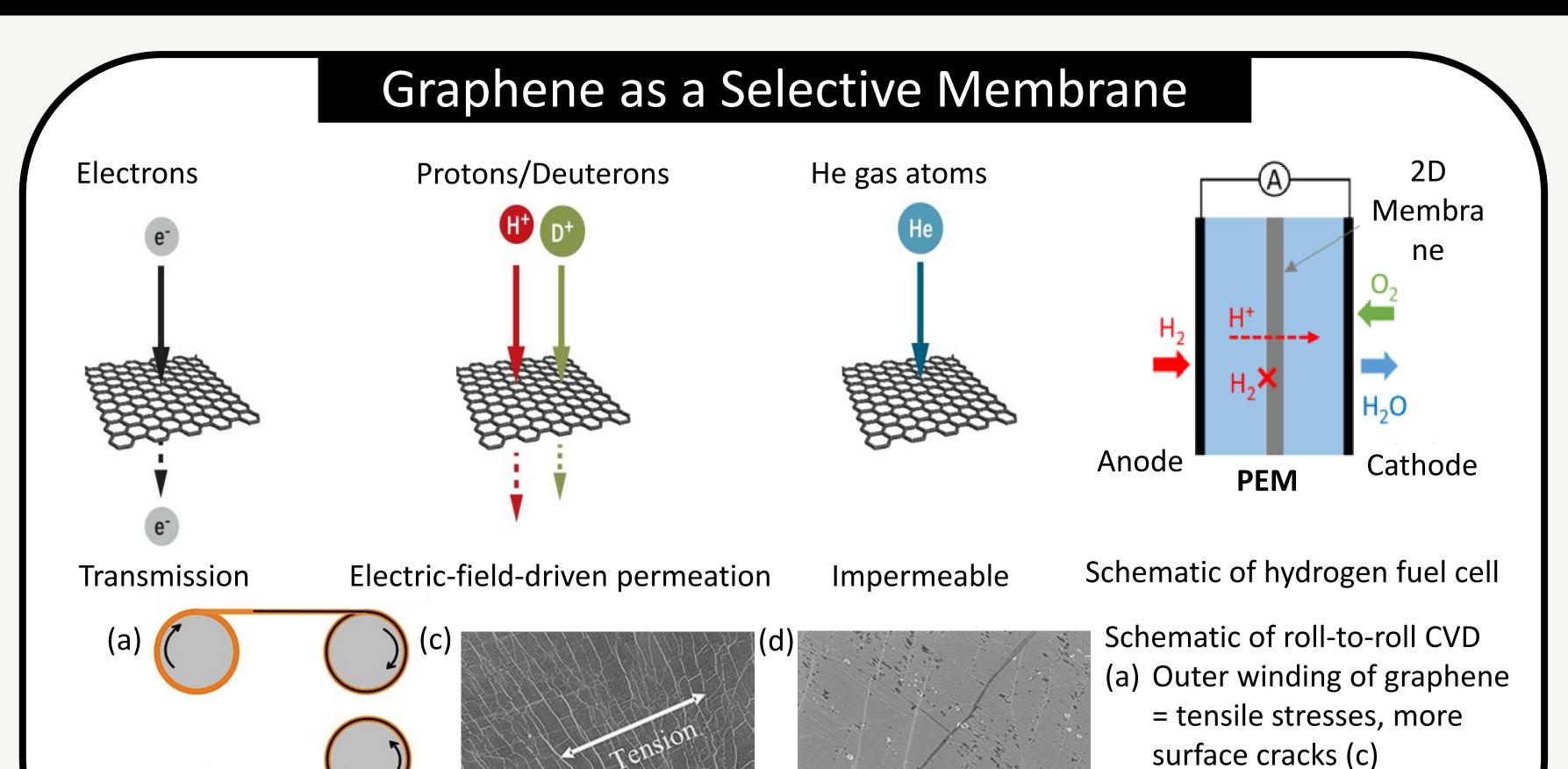


Rahul Shah¹, Pavan Chaturvedi², Nicole Moehring^{1,2}, Piran R Kidambi^{1,2}

¹Interdisciplinary Material Science, Vanderbilt University, Nashville, TN, 37235, USA ²Chemical and Biomolecular Engineering Department, Vanderbilt University, Nashville, TN, 37212, USA





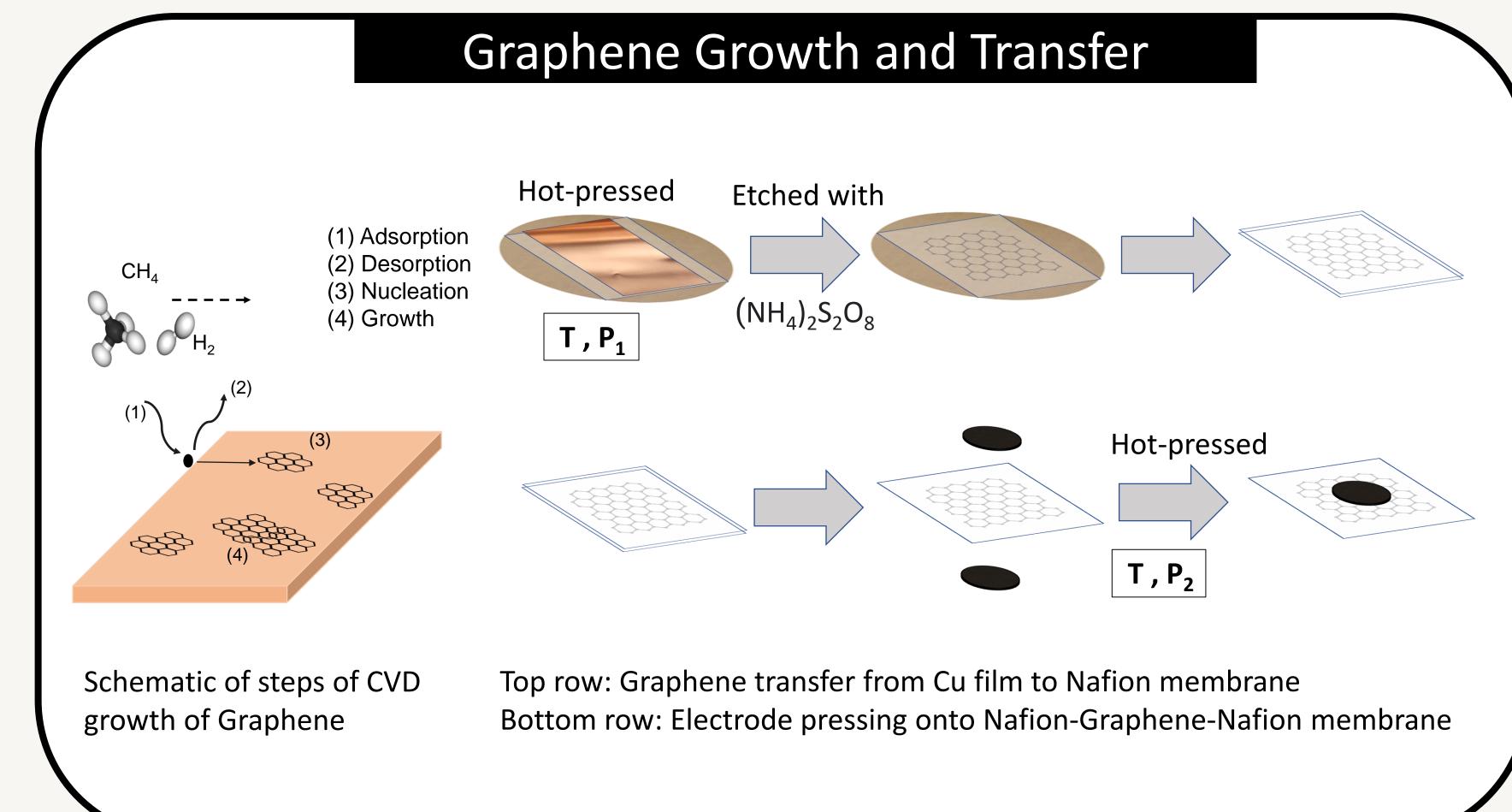


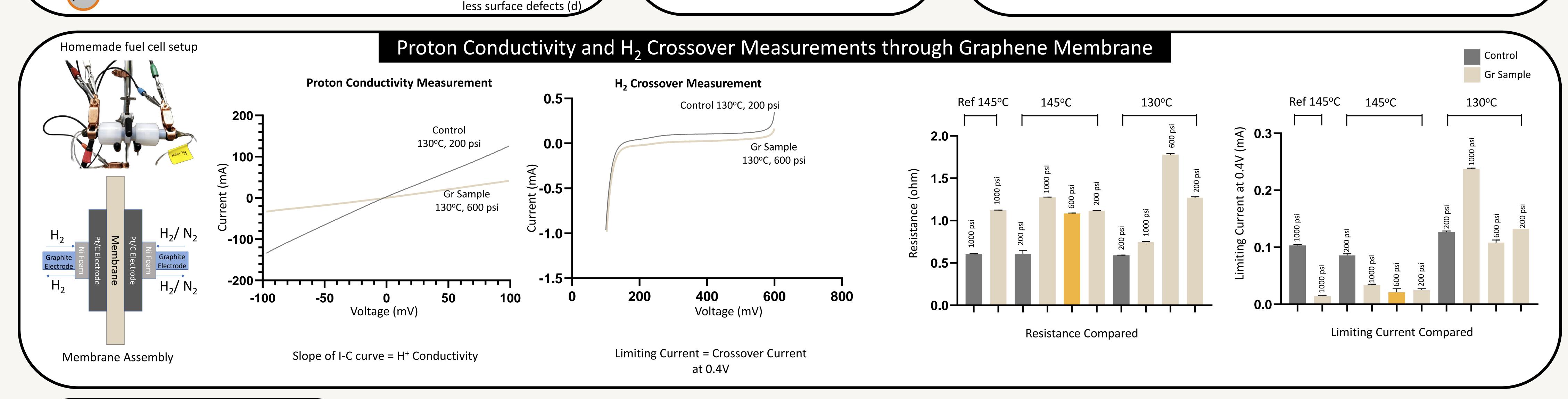
(b) Inner winding of graphene

= compressive stresses,

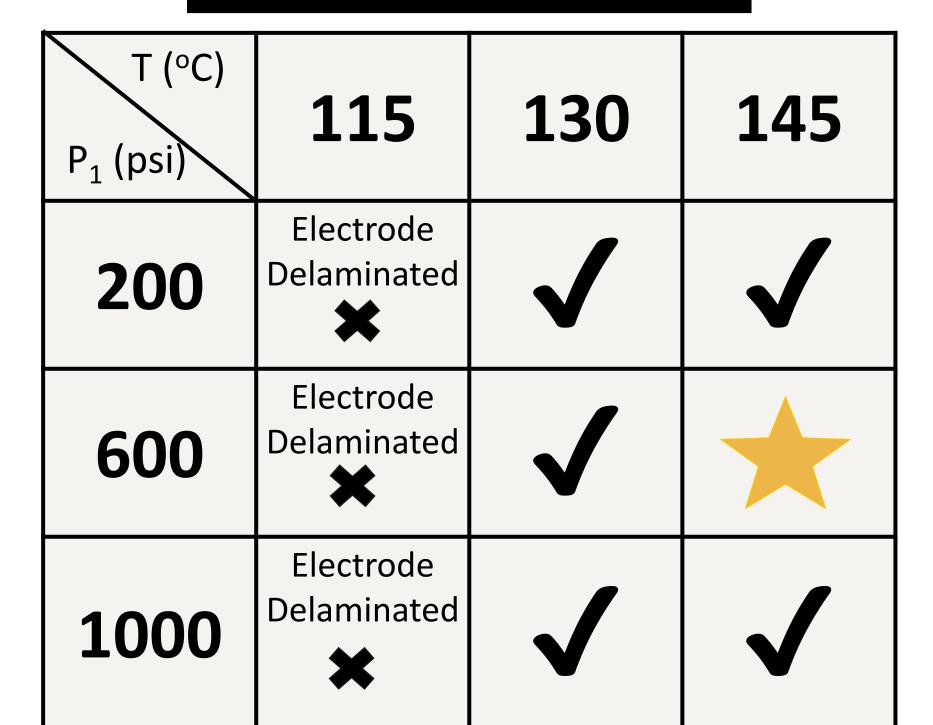
Why defects matter? (a) (b) 5 nm (a) SEM and (b) STM micrograph of Graphene grown on Cu (circle = atomic scale defect) Ideal proton exchange membrane: (1) high H+ conductivity and (2) low H2 crossover.

Surface defects can affect both these factors









(c)

Electrodes were pressed for all sample at the same T and $P_2 = 200$ psi

Conclusions

Nafion

(a) Graphene transferred onto nafion on PTFE

(c) Electrodes hot pressed onto membrane

(d) Electrodes delaminating from membrane.

(b) Graphene on Nafion

Ideal proton exchange membrane = LOW resistance to H⁺ transport, LOW H₂ crossover

Graphene transfer onto nafion successful at T = 115°C, 130°C and 145°C

Electrode pressing onto membrane failed at T = 115°C

Gas phase measurements show that pressing parameters influence surface defects

From the studied parameters, membrane fabricated with hot-press conditions of 145°C and 600 psi showed best performance

Acknowledgement

I would like to thank Prof. Piran Kidambi and all members of Kidambi Lab for their support and guidance during this 10-week rotation. Special thanks to Pavan and Nicole for being the best mentors.

Sincere appreciation for Prof. Josh Caldwell and Sarah Ross for their support during this first semester at the IMS program at Vanderbilt.

Thanks to VINSE for SEM imaging facility.

References

- . Kidambi, P.R. ,et al. Science 374, 708 (2021)
- 2. Peifu Cheng, et al. Nanoscale, **13**, 2825-2837 (2021)
- Peifu Cheng, et al. Nanoscale, 13, 2825-2837 (2021)
 Kidambi, P.R. ,et al. ACS Applied Materials & Interfaces 10 (12), 10369-10378 (2018)
- 4. Eoin Griffin, et al. ACS Nano 14 (6), 7280-7286 (2020)
- 5. Nicole K. Moehring, et al. ACS Nano 16 (10), 16003-16018 (2022)